

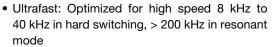
# INT-A-PAK™ "Half-Bridge" (Ultrafast Speed IGBT), 100 A



PRODUCT SUMMARY			
V <sub>CES</sub>	1200 V		
I <sub>C</sub> DC	182 A		
V <sub>CE(on)</sub> at 100 A, 25 °C	2.25 V		

#### **FEATURES**

Generation 4 IGBT technology





- Very low conduction and switching losses
- HEXFRED® antiparallel diodes with ultrasoft recovery
- Industry standard package
- UL approved file E78996
- · Designed and qualified for industrial level
- Material categorization: For definitions of compliance please see www.vishay.com/doc?99912

#### **BENEFITS**

- · Increased operating efficiency
- · Direct mounting to heatsink
- Performance optimized for power conversion: UPS, SMPS, welding
- Lower EMI, requires less snubbing

ABSOLUTE MAXIMUM RATINGS					
PARAMETER	SYMBOL	TEST CONDITIONS	MAX.	UNITS	
Collector to emitter voltage	V <sub>CES</sub>		1200	V	
Continuous collector current	I <sub>C</sub>	T <sub>C</sub> = 25 °C	182		
Continuous collector current		T <sub>C</sub> = 93 °C	100		
Pulsed collector current	I <sub>CM</sub>	Repetitive rating; V <sub>GE</sub> = 20 V, pulse width limited by maximum junction temperature	200	А	
Peak switching current See fig. 17	I <sub>LM</sub>		200		
Peak diode forward current	I <sub>FM</sub>		200		
Gate to emitter voltage	$V_{GE}$		± 20	V	
RMS isolation voltage	V <sub>ISOL</sub>	Any terminal to case, t = 1 minute	2500	V	
Maximum power dissipation	P <sub>D</sub>	T <sub>C</sub> = 25 °C	520	w	
		T <sub>C</sub> = 85 °C	270		
Operating junction temperature range	TJ		- 40 to + 150	°C	
Storage temperature range	T <sub>Stg</sub>		- 40 to + 125	1	



<b>ELECTRICAL SPECIFICATIONS</b> (T <sub>J</sub> = 25 °C unless otherwise specified)						
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNITS
Collector to emitter breakdown voltage	V <sub>(BR)CES</sub>	V <sub>GE</sub> = 0 V, I <sub>C</sub> = 1 mA	1200	-	-	
Outlies to the contitue of the continue of	V <sub>CE(on)</sub>	V <sub>GE</sub> = 15 V, I <sub>C</sub> = 100 A	-	2.25	3	V
Collector to emitter voltage		V <sub>GE</sub> = 15 V, I <sub>C</sub> = 100 A, T <sub>J</sub> = 125 °C	-	2	2.4	
Gate threshold voltage	V <sub>GE(th)</sub>	I <sub>C</sub> = 1.25 mA	3.0	4.4	6.0	
Temperature coefficient of threshold voltage	$\Delta V_{GE(th)}/\Delta T_{J}$	$V_{CE} = V_{GE}$ , $I_C = 1.25$ mA	-	- 12	-	mV/°C
Forward transconductance	9 <sub>fe</sub>	$V_{CE} = 25 \text{ V}, I_{C} = 100 \text{ A}$ Pulse width 50 µs, single shot	-	136	-	S
Collector to emitter leaking current	I <sub>CES</sub>	V <sub>GE</sub> = 0 V, V <sub>CE</sub> = 1200 V	-	0.03	1.0	mA
		V <sub>GE</sub> = 0 V, V <sub>CE</sub> = 1200 V, T <sub>J</sub> = 125 °C	-	4.2	10	
Maximum diode forward voltage	V <sub>FM</sub>	V <sub>GE</sub> = 0 V, I <sub>F</sub> = 100 A	-	3.3	4.0	V
		V <sub>GE</sub> = 0 V, I <sub>F</sub> = 100 A, T <sub>J</sub> = 125 °C	-	3.2	3.8	
Gate to emitter leakage current	I <sub>GES</sub>	V <sub>GE</sub> = ± 20 V	-	-	250	nA

PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNITS
Total gate charge (turn-on)	Qg		-	830	1245	nC
Gate to emitter charge (turn-on)	Q <sub>ge</sub>	$V_{CC} = 400 \text{ V}$ $I_{C} = 124 \text{ A}$	-	140	210	
Gate to collector charge (turn-on)	Q <sub>gc</sub>	IC = 124 A	-	275	412	
Turn-on delay time	t <sub>d(on)</sub>		-	570	-	- ns
Rise time	t <sub>r</sub>	$R_{g1} = 15 \Omega$	-	85	-	
Turn-off delay time	t <sub>d(off)</sub>	$R_{g2} = 0 \Omega$	-	581	-	
Fall time	t <sub>f</sub>	I <sub>C</sub> = 100 A V <sub>CC</sub> = 720 V	-	276	-	
Turn-on switching energy	E <sub>on</sub>	$V_{GE} = \pm 15 \text{ V}$	-	7.6	-	mJ
Turn-off switching energy	E <sub>off</sub> <sup>(1)</sup>	T <sub>J</sub> = 25 °C	-	6.8	-	
Total switching energy	E <sub>ts</sub> <sup>(1)</sup>		-	14.4	-	
Turn-on delay time	t <sub>d(on)</sub>		-	571	-	- ns
Rise time	t <sub>r</sub>	$R_{g1} = 15 \Omega$ $R_{g2} = 0 \Omega$ $I_C = 100 A$ $V_{CC} = 720 V$ $V_{GE} = \pm 15 V$	-	89	-	
Turn-off delay time	t <sub>d(off)</sub>		-	606	-	
Fall time	t <sub>f</sub>		-	649	-	
Turn-on switching energy	E <sub>on</sub>		-	10	-	
Turn-off switching energy	E <sub>off</sub> <sup>(1)</sup>	T <sub>J</sub> = 125 °C	-	16	-	mJ
Total switching energy	E <sub>ts</sub> (1)		-	26	45	
Input capacitance	C <sub>ies</sub>	V <sub>GF</sub> = 0 V	-	18 672	-	
Output capacitance	C <sub>oes</sub>	$V_{CC} = 30 \text{ V}$ f = 1 MHz	-	830	-	рF
Reverse transfer capacitance	C <sub>res</sub>		-	161	-	
Diode reverse recovery time	t <sub>rr</sub>	$I_C = 100 \text{ A}$ $R_{g1} = 15 \Omega$	-	149	-	ns
Diode peak reverse current	I <sub>rr</sub>		-	104	-	Α
Diode recovery charge	Q <sub>rr</sub>	$R_{g2} = 0 \Omega$ $V_{CC} = 720 V$	-	7664	-	nC
Diode peak rate of fall of recovery during t <sub>b</sub>	dl <sub>(rec)M</sub> /dt	dl/dt = 1300 A/µs	-	1916	-	A/μs

### Note

 $<sup>^{(1)}</sup>$  Repetitive rating;  $V_{GE}$  = 20 V, pulse width limited by maximum junction temperature



THERMAL AND MECHANICAL SPECIFICATIONS						
PARAMETER		SYMBOL	TEST CONDITIONS	TYP.	MAX.	UNITS
Thermal resistance, junction to case Diode		R <sub>thJC</sub>		-	0.24	°C/W
				-	0.35	
Thermal resistance, case to sink per module		R <sub>thCS</sub>		0.1	-	
Mounting torque	case to heatsink			-	4.0	Nima
	case to terminal 1, 2 and 3		For screws M5 x 0.8	-	3.0	Nm
Weight of module				200	-	g

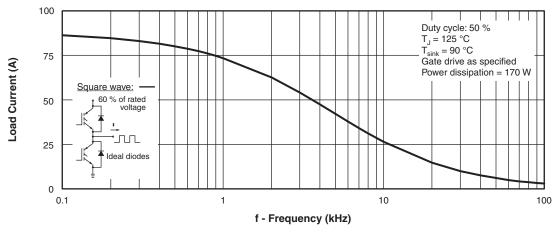


Fig. 1 - Typical Load Current vs. Frequency (Load Current = I<sub>RMS</sub> of Fundamental)

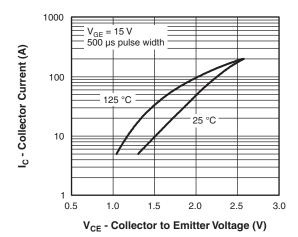


Fig. 2 - Typical Output Characteristics

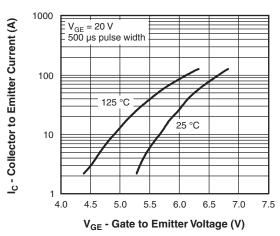


Fig. 3 - Typical Transfer Characteristics



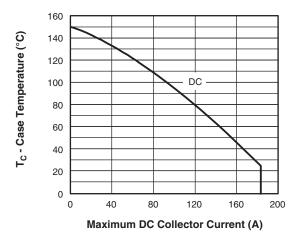


Fig. 4 - Case Temperature vs. Maximum Collector Current

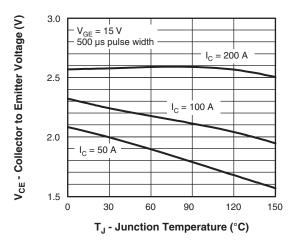


Fig. 5 - Typical Collector to Emitter Voltage vs. Junction Temperature

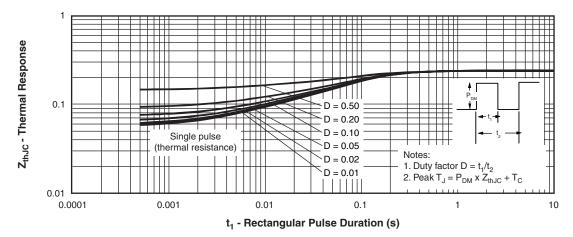


Fig. 6 - Maximum Effective Transient Thermal Impedance, Junction to Case

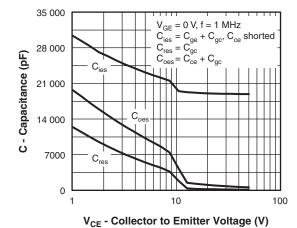


Fig. 7 - Typical Capacitance vs. Collector to Emitter Voltage

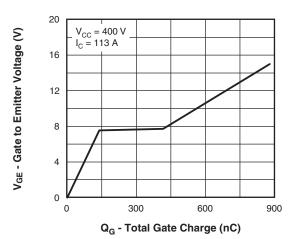


Fig. 8 - Typical Gate Charge vs. Gate to Emitter Voltage

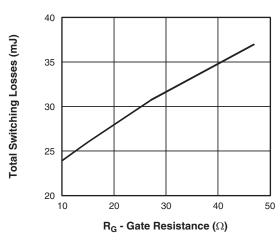


Fig. 9 - Typical Switching Losses vs. Gate Resistance

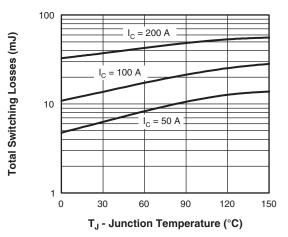


Fig. 10 - Typical Switching Losses vs. Junction Temperature

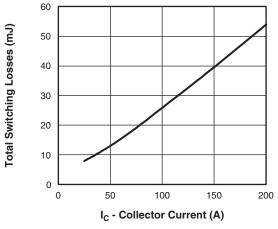
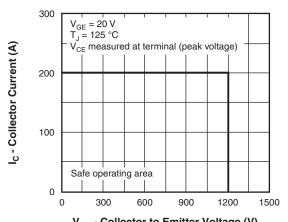


Fig. 11 - Typical Switching Losses vs. Collector Current



V<sub>CE</sub> - Collector to Emitter Voltage (V)

Fig. 12 - Reverse Bias SOA

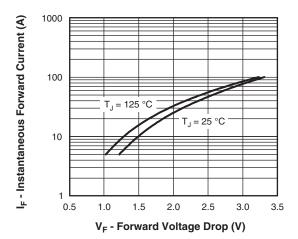


Fig. 13 - Typical Forward Voltage Drop vs. Instantaneous Forward Current

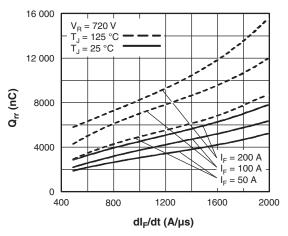


Fig. 14 - Typical Stored Charge vs. dl<sub>F</sub>/dt

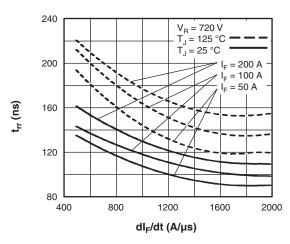


Fig. 15 - Typical Reverse Recovery Time vs. dl<sub>F</sub>/dt

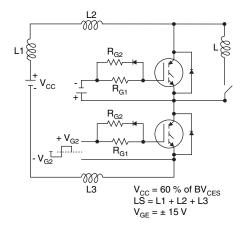


Fig. 17a - Test Circuit for Measurement of  $I_{LM}$ ,  $E_{on}$ ,  $E_{off(diode)}$ ,  $t_{rr}$ ,  $Q_{rr}$ ,  $I_{rr}$ ,  $t_{d(on)}$ ,  $t_r$ ,  $t_{d(off)}$ ,  $t_f$ 

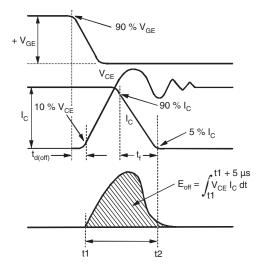


Fig. 17b - Test Waveforms for Circuit of Fig. 18a, Defining  $E_{\text{off}}$ ,  $t_{\text{d(off)}}$ ,  $t_{\text{f}}$ 

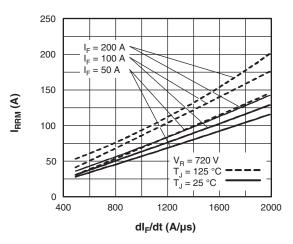


Fig. 16 - Typical Recovery Current vs. dl<sub>F</sub>/dt

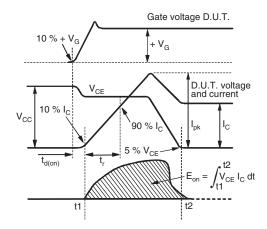


Fig. 17c - Test Waveforms for Circuit of Fig. 18a, Defining  $E_{on}$ ,  $t_{d(on)}$ ,  $t_{r}$ 

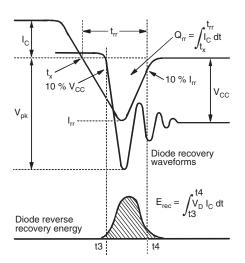


Fig. 17d - Test Waveforms for Circuit of Fig. 18a, Defining E<sub>rec</sub>, t<sub>rr</sub>, Q<sub>rr</sub>, I<sub>rr</sub>

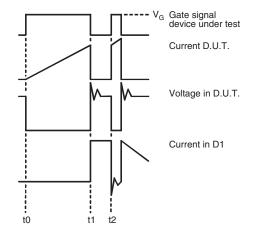
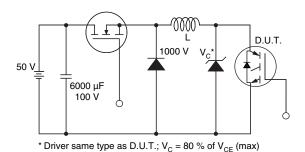


Fig. 17e - Macro Waveforms for Figure 18a's Test Circuit



Note: Due to the 50 V power supply, pulse width and inductor will increase to obtain rated  $I_{\rm d}$ 

Fig. 18 - Clamped Inductive Load Test Circuit

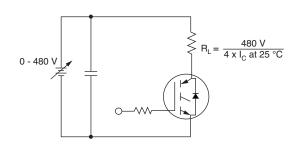
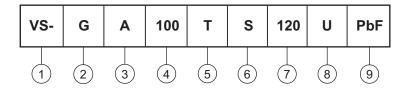


Fig. 19 - Pulsed Collector Current Test Circuit

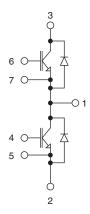
#### **ORDERING INFORMATION TABLE**

### Device code



- Vishay Semiconductors product
- 2 Insulated gate bipolar transistor (IGBT)
- Generation 4, IGBT silicon, DBC construction
- Current rating (100 = 100 A)
- 5 Circuit configuration (T = Half-bridge)
- 6 Package indicator (INT-A-PAK)
- 7 Voltage rating (120 = 1200 V)
- Speed/type (U = Ultrafast)
- 9 PbF = Lead (Pb)-free

### **CIRCUIT CONFIGURATION**

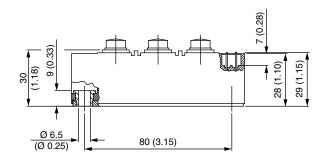


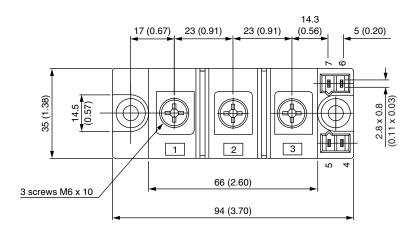
LINKS TO RELATED DOCUMENTS				
Dimensions	www.vishay.com/doc?95173			

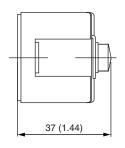


## **INT-A-PAK IGBT**

### **DIMENSIONS** in millimeters (inches)







Document Number: 95173 Revision: 04-May-09





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